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Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/516,797	YANASHIMA ET AL.	
Examiner	Art Unit	
B. Chen	1762	

	SEARCHED		
Class	Subclass	Date ·	Examiner
427	248.1 255.6	9/7/2005	вс

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

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west	9/7/2005	вс